

Search Notes

Application/Control No.

10/051,267

Examiner

Thien F. Tran

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	59, 66	3/16/2005	TT
257	70, 72	3/16/2005	TT
257	75	3/16/2005	TT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
257	59, 66	3/16/2005	TT
257	70, 72	3/16/2005	TT
257	75	3/16/2005	TT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR